

Amendment to the Claims:

This listing of claims 1-10 will replace all prior versions, and listing of claims in the application.

Listing of Claims

1. (Original) A method of reconstructing a surface of an object; the object being represented by a 2-dimensional grid of measurements, where for each grid point the measurements include corresponding information on a first slope of the surface in a first direction and a second slope of the surface in a different second direction; the method including selecting a 2-dimensional part of the grid and fitting a corresponding part of the surface to the measurements of all grid points in the selected part, where the fitting for each grid point of the selected part is based on both the corresponding first and second slope information.
2. (Original) A method as claimed in claim 1, including performing the fitting through a least-square minimization operation.
3. (Original) A method as claimed in claim 2, including performing the least square minimization operation by solving an equation that describes a shape of a soap film loaded with a pressure field equal to a divergence of a slope vector including the first and second slope information.

4. (Original) A method as claimed in claim 1, wherein the selected part of the grid is substantially the entire grid.

5. (Original) A method as claimed in claim 1, including measuring for each point of the grid the first and second slope using deflectometry.

6. (Original) A computer program product operative to cause a processor to perform the steps of the method as claimed in claim 1.

7. (Original) A system for reconstructing a surface of an object including: an input for receiving a 2-dimensional grid of measurements representing a surface of an object, where for each grid point the measurements include corresponding information on a first slope of the surface in a first direction and a second slope of the surface in a different second direction; a processor for, under control of a program, selecting a 2-dimensional part of the grid and fitting a corresponding part of the surface to the measurements of all grid points in the selected part, where the fitting for each grid point of the selected part is based on both the corresponding first and second slope information; and an output for providing a representation of at least the reconstructed surface part.

8. (Original) A system as claimed in claim 7, wherein the system includes a measurement

unit for measuring for each measurement point of a measurement grid the corresponding first and second slope information.

9. (Original) A system as claimed in claim 8, wherein the measuring is performed along non-straight lines; the measurement grid being directly used for the reconstruction.

10. (Original) A system as claimed in claim 8, wherein the system the measurement unit includes a deflectometry measurement unit.

11. (New) A method of reconstructing a surface of an object; the object being represented by a 2-dimensional grid of measurements, where for each grid point the measurements include corresponding information on a first slope of the surface in a first direction and a second slope of the surface in a different second direction; the method including selecting a 2-dimensional part of the grid and fitting a corresponding part of the surface to the measurements of all grid points in the selected part, where the fitting for each grid point of the selected part is based on both the corresponding first and second slope information whereby said fitting is performed through a least-square minimization operation by solving an equation that describes a shape of a soap film loaded with a pressure field equal to a divergence of a slope vector including the first and second slope information.

12. (New) A system for reconstructing a surface of an object including: an input for receiving a 2-dimensional grid of measurements representing a surface of an object, where for each grid point the measurements include corresponding information on a first slope of the surface in a first direction and a second slope of the surface in a different second direction; a processor for, under control of a program, selecting a 2-dimensional part of the grid and fitting a corresponding part of the surface to the measurements of all grid points in the selected part, where the fitting for each grid point of the selected part is based on both the corresponding first and second slope information; and an output for providing a representation of at least the reconstructed surface part, wherein the system includes a measurement unit for measuring for each measurement point of a measurement grid the corresponding first and second slope information and wherein the), wherein the system the measurement unit includes a deflectometry measurement unit.